# IGBT - Field Stop, Trench 650 V, 75 A

## FGH75T65SQDT

#### Description

Using novel field stop IGBT technology, ON Semiconductor's new series of field stop 4<sup>th</sup> generation IGBTs offer the optimum performance for solar inverter, UPS, welder, telecom, ESS and PFC applications where low conduction and switching losses are essential.

#### **Features**

- Max Junction Temperature  $T_J = 175^{\circ}C$
- Positive Temperature Co-efficient for Easy Parallel Operating
- High Current Capability
- Low Saturation Voltage:  $V_{CE(sat)} = 1.6 \text{ V (Typ.)} @ I_C = 75 \text{ A}$
- 100% of the Parts Tested for I<sub>LM</sub>
- High Input Impedance
- Fast Switching
- Tighten Parameter Distribution
- This Device is Pb-Free and is RoHS Compliant

#### **Applications**

• Solar Inverter, UPS, Welder, Telecom, ESS, PFC

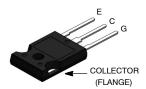


#### ON Semiconductor®

#### www.onsemi.com

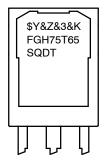
V <sub>CES</sub>	Ic
650 V	75 A





TO-247-3LD CASE 340CH

#### **MARKING DIAGRAM**



\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = Numeric Date Code

&K = Lot Code

FGH75T65SQDT = Specific Device Code

#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 2 of this data sheet.

#### **ABSOLUTE MAXIMUM RATINGS**

Symbol	Description		FGH50T65SQD-F155	Unit
V <sub>CES</sub>	Collector to Emitter Voltage		650	V
V <sub>GES</sub>	Gate to Emitter Voltage		±20	V
	Transient Gate to Emitter Voltage		±30	V
I <sub>C</sub>	Collector Current	T <sub>C</sub> = 25°C	150	Α
		T <sub>C</sub> = 100°C	75	Α
I <sub>LM</sub> (Note 1)	Pulsed Collector Current	T <sub>C</sub> = 25°C	300	Α
I <sub>CM</sub> (Note 2)	Pulsed Collector Current		300	Α
I <sub>F</sub>	Diode Forward Current	T <sub>C</sub> = 25°C	150	Α
	Diode Forward Current	T <sub>C</sub> = 100°C	75	Α
I <sub>FM</sub>	Pulsed Diode Maximum Forward Current		300	Α
$P_{D}$	Maximum Power Dissipation	T <sub>C</sub> = 25°C	375	W
	l	T <sub>C</sub> = 100°C	188	W
TJ	Operating Junction Temperature		-55 to +175	°C
T <sub>STG</sub>	Storage Temperature Range		-55 to +175	°C
TL	Maximum Lead Temp. for Soldering Purposes,	1/8" from Case for 5 Seconds	300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1.  $V_{CC} = 400 \text{ V}$ ,  $V_{GE} = 15 \text{ V}$ ,  $I_{C} = 300 \text{ A}$ ,  $R_{G} = 21 \Omega$ , Inductive Load.

2. Repetitive rating: Pulse width limited by max. junction temperature.

#### THERMAL CHARACTERISTICS

Symbol	Parameter	FGH75T65SQDT-F155	Unit
R <sub>θJC</sub> (IGBT)	Thermal Resistance, Junction to Case, Max.	0.4	°C/W
R <sub>θJC</sub> (Diode)	Thermal Resistance, Junction to Case, Max.	0.65	°C/W
$R_{ hetaJA}$	Thermal Resistance, Junction to Ambient, Max.	40	°C/W

## PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Qty per Tube
FGH75T65SQDT-F155	FGH75T65SQDT	TO-247-3LD	Tube	ı	İ	30

## **ELECTRICAL CHARACTERISTICS OF THE IGBT** (T<sub>C</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
OFF CHARACT	ERISTICS					1
BV <sub>CES</sub>	Collector to Emitter Breakdown Voltage	$V_{GE} = 0 \text{ V}, I_C = 1 \text{ mA}$	650	_	_	V
$\Delta BV_{CES}/\Delta T_{J}$	Temperature Coefficient of Breakdown Voltage	I <sub>C</sub> = 1 mA, Reference to 25°C	-	0.6	-	V/°C
I <sub>CES</sub>	Collector Cut-Off Current	V <sub>CE</sub> = V <sub>CES</sub> , V <sub>GE</sub> = 0 V	-	-	250	μΑ
I <sub>GES</sub>	G-E Leakage Current	$V_{GE} = V_{GES}$ , $V_{CE} = 0 V$	_	-	±400	nA
ON CHARACTE	RISTICS	•		•		•
V <sub>GE(th)</sub>	G-E Threshold Voltage	$I_C$ = 75 mA, $V_{CE}$ = $V_{GE}$	2.6	4.5	6.4	V
V <sub>CE(sat)</sub>	Collector to Emitter Saturation Voltage	I <sub>C</sub> = 75 A, V <sub>GE</sub> = 15 V, T <sub>C</sub> = 25 °C	-	1.6	2.1	V
		I <sub>C</sub> = 75 A, V <sub>GE</sub> = 15 V, T <sub>C</sub> = 175°C	-	1.92	-	V
DYNAMIC CHAI	RACTERISTICS					
C <sub>ies</sub>	Input Capacitance	V <sub>CE</sub> = 30 V, V <sub>GE</sub> = 0 V, f = 1MHz	-	4845	-	pF
C <sub>oes</sub>	Output Capacitance		-	155	-	pF
C <sub>res</sub>	Reverse Transfer Capacitance	1	-	14	-	pF
SWITCHING CH	IARACTERISTICS					
T <sub>d(on)</sub>	Turn-On Delay Time	$V_{CC} = 400 \text{ V, } I_{C} = 18.8 \text{ A,}$ $R_{G} = 4.7 \Omega, V_{GE} = 15 \text{ V,}$ Inductive Load, $T_{C} = 25^{\circ}\text{C}$	-	23	-	ns
T <sub>r</sub>	Rise Time		-	10	-	ns
T <sub>d(off)</sub>	Turn-Off Delay Time		-	120	-	ns
T <sub>f</sub>	Fall Time		-	7	-	ns
E <sub>on</sub>	Turn-On Switching Loss		-	300	_	μJ
E <sub>off</sub>	Turn-Off Switching Loss		-	70	-	μJ
E <sub>ts</sub>	Total Switching Loss		-	370	-	μJ
T <sub>d(on)</sub>	Turn-On Delay Time	$V_{CC} = 400 \text{ V}, I_C = 37.5 \text{ A},$	-	26	-	ns
T <sub>r</sub>	Rise Time	$R_G = 4.7 \Omega$ , $V_{GE} = 15 V$ , Inductive Load, $T_C = 25^{\circ}C$	-	19	-	ns
T <sub>d(off)</sub>	Turn-Off Delay Time	1	-	114	-	ns
T <sub>f</sub>	Fall Time		-	11	-	ns
E <sub>on</sub>	Turn-On Switching Loss		-	746	-	μJ
E <sub>off</sub>	Turn-Off Switching Loss		-	181	-	μJ
E <sub>ts</sub>	Total Switching Loss		-	927	-	μJ
T <sub>d(on)</sub>	Turn-On Delay Time	$V_{CC}$ = 400 V, $I_{C}$ = 18.5 A, $R_{G}$ = 4.7 $\Omega$ , $V_{GE}$ = 15 V,	-	22	-	ns
T <sub>r</sub>	Rise Time	Inductive Load, T <sub>C</sub> = 175°C	-	12	-	ns
T <sub>d(off)</sub>	Turn-Off Delay Time	]	-	135	-	ns
T <sub>f</sub>	Fall Time	1	-	14	-	ns
E <sub>on</sub>	Turn-On Switching Loss	]	-	760	-	μJ
E <sub>off</sub>	Turn-Off Switching Loss	1	-	180	-	μJ
E <sub>ts</sub>	Total Switching Loss	┥		940	_	μJ

#### ELECTRICAL CHARACTERISTICS OF THE IGBT (T<sub>C</sub> = 25°C unless otherwise noted) (continued)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit	
SWITCHING CI	SWITCHING CHARACTERISTICS						
T <sub>d(on)</sub>	Turn-On Delay Time	$V_{CC} = 400 \text{ V}, I_C = 37.5 \text{ A},$ $R_G = 4.7 \Omega, V_{GE} = 15 \text{ V},$	-	24	-	ns	
T <sub>r</sub>	Rise Time	Inductive Load, T <sub>C</sub> = 175°C	-	24	_	ns	
T <sub>d(off)</sub>	Turn-Off Delay Time		-	125	_	ns	
T <sub>f</sub>	Fall Time		-	10	-	ns	
E <sub>on</sub>	Turn-On Switching Loss		-	1520	ı	μЈ	
E <sub>off</sub>	Turn-Off Switching Loss		-	401	-	μJ	
E <sub>ts</sub>	Total Switching Loss		-	1921	-	μJ	
Qg	Total Gate Charge	V <sub>CE</sub> = 400 V, I <sub>C</sub> = 75 A, V <sub>GE</sub> = 15 V	-	128	-	nC	
Q <sub>ge</sub>	Gate to Emitter Charge	1 V GE - 10 V	-	23	-	nC	
Q <sub>gc</sub>	Gate to Collector Charge		-	29	-	nC	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

## **ELECTRICAL CHARACTERISTICS OF THE DIODE** ( $T_C = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Co	nditions	Min	Тур	Max	Unit
$V_{FM}$	Diode Forward Voltage	I <sub>F</sub> = 75 A	T <sub>C</sub> = 25°C	-	1.8	2.1	V
			T <sub>C</sub> = 175°C	-	1.7	-	
E <sub>rec</sub>	Reverse Recovery Energy	I <sub>F</sub> = 75 A, dI <sub>F</sub> /dt = 200 A/μs	T <sub>C</sub> = 175°C	-	160	-	μJ
T <sub>rr</sub>	Diode Reverse Recovery Time	αιργαί – 200 Αγμο	T <sub>C</sub> = 25°C	-	76	-	ns
			T <sub>C</sub> = 175°C	-	270	-	
Q <sub>rr</sub>	Diode Reverse Recovery Charge	1	T <sub>C</sub> = 25°C	-	206	-	nC
			T <sub>C</sub> = 175°C	-	2199	-	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

#### **TYPICAL CHARACTERISTICS**

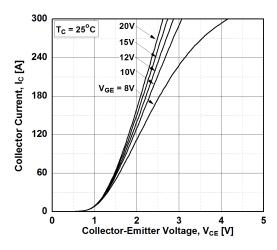


Figure 1. Typical Output Characteristics

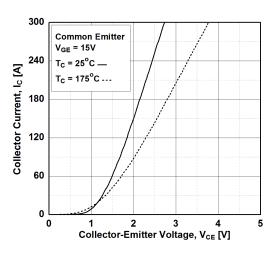


Figure 3. Typical Saturation Voltage Characteristics

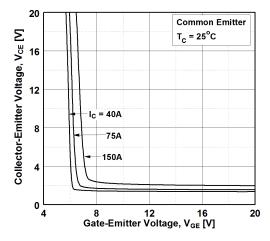


Figure 5. Saturation Voltage vs. V<sub>GE</sub>

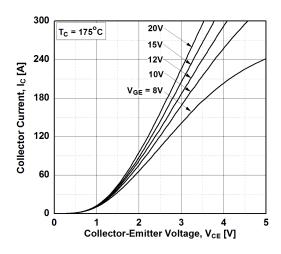


Figure 2. Typical Output Characteristics

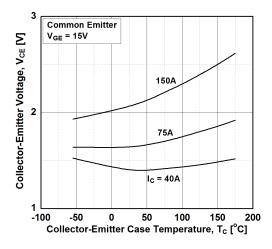


Figure 4. Saturation Voltage vs. Case Temperature at Variant Current Level

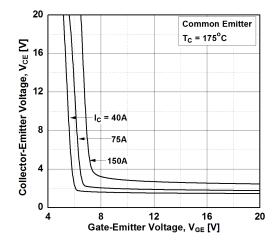


Figure 6. Saturation Voltage vs. V<sub>GE</sub>

#### TYPICAL CHARACTERISTICS (Continued)

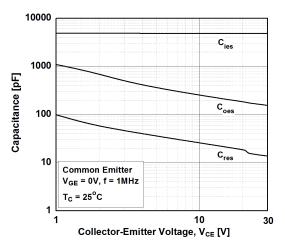


Figure 7. Capacitance Characteristics

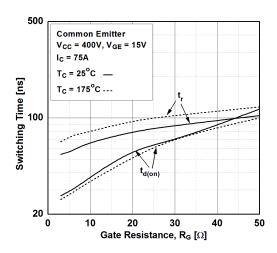


Figure 9. Turn-on Characteristics vs.

Gate Resistance

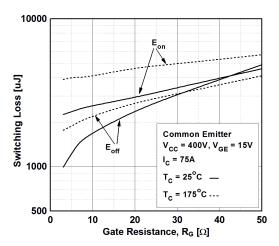


Figure 11. Switching Loss vs.
Gate Resistance

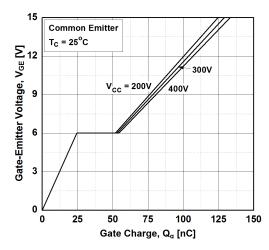


Figure 8. Gate Charge Characteristics

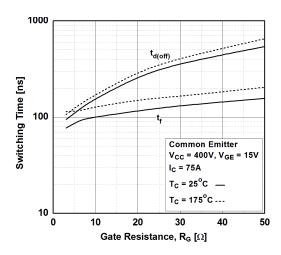


Figure 10. Turn-off Characteristics vs. Gate Resistance

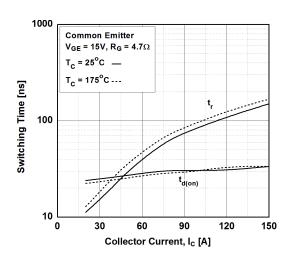


Figure 12. Turn-on Characteristics vs. Collector Current

#### TYPICAL CHARACTERISTICS (Continued)

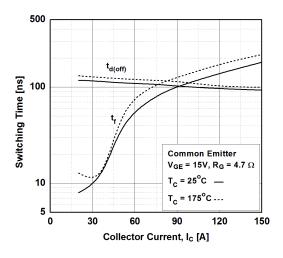


Figure 13. Turn-off Characteristics vs. Collector Current

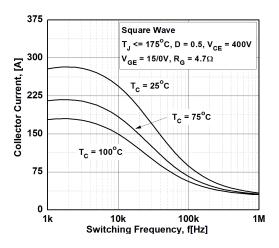


Figure 15. Load Current vs. Frequency

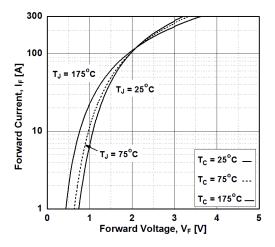


Figure 17. Forward Characteristics

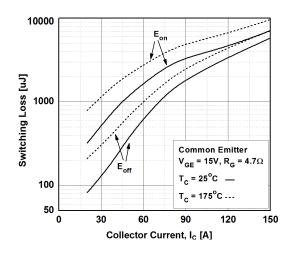


Figure 14. Switching Loss vs. Collector Current

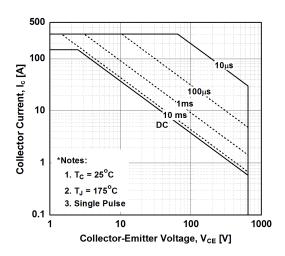
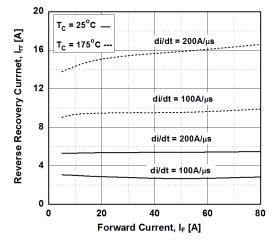
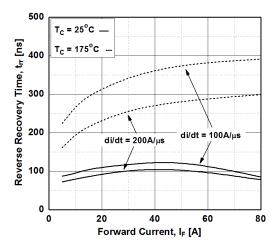


Figure 16. SOA Characteristics



**Figure 18. Reverse Recovery Current** 

#### TYPICAL CHARACTERISTICS (Continued)



2500
T<sub>C</sub> = 25°C —
T<sub>C</sub> = 175°C —
T

Figure 19. Reverse Recovery Time

Figure 20. Stored Charge

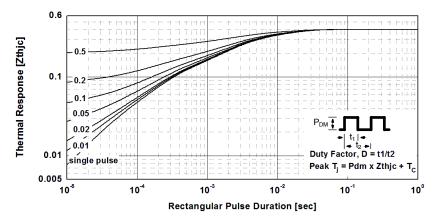


Figure 21. Transient Thermal Impedance of IGBT

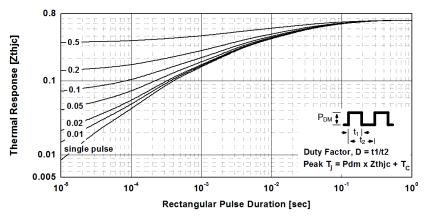
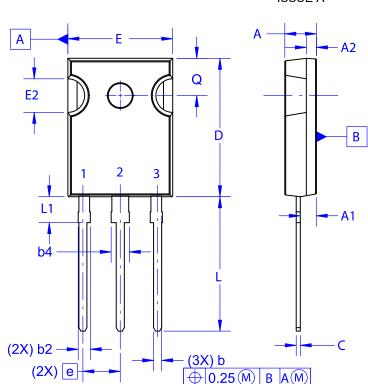


Figure 22. Transient Thermal Impedance of Diode

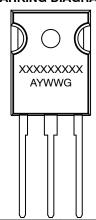
#### TO-247-3LD CASE 340CH **ISSUE A**





- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 2009.
  D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

### GENERIC **MARKING DIAGRAM\***



XXXX = Specific Device Code

= Assembly Location

WW = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

	DATE	09 OCT 2019
Ø P —		P1 D2
S E1 —	2	D1
		<u>.</u>

DIM	MILLIMETERS				
DIM	MIN	NOM	MAX		
Α	4.58	4.70	4.82		
<b>A</b> 1	2.29	2.475	2.66		
A2	1.40	1.50	1.60		
D	20.32	20.57	20.82		
Е	15.37	15.62	15.87		
E2	4.96	5.08	5.20		
е	~	5.56	~		
L	19.75	20.00	20.25		
L1	3.69	3.81	3.93		
ØΡ	3.51	3.58	3.65		
Q	5.34	5.46	5.58		
S	5.34	5.46	5.58		
b	1.17	1.26	1.35		
b2	1.53	1.65	1.77		
b4	2.42	2.54	2.66		
С	0.51	0.61	0.71		
D1	13.08	~	~		
D2	0.51	0.93	1.35		
E1	12.81	~	~		
ØP1	6.61	6.73	6.85		

DOCUMENT NUMBER:	98AON13853G	Electronic versions are uncontrolled except when accessed directly from the Document Reportance Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.			
DESCRIPTION:	TO-247-3LD		PAGE 1 OF 1		

ON Semiconductor and un are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

ON Semiconductor and the are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <a href="www.onsemi.com/site/pdf/Patent-Marking.pdf">www.onsemi.com/site/pdf/Patent-Marking.pdf</a>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor and see no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and

#### **PUBLICATION ORDERING INFORMATION**

LITERATURE FULFILLMENT:
Email Requests to: orderlit@onsemi.com

ON Semiconductor Website: www.onsemi.com

TECHNICAL SUPPORT North American Technical Support: Voice Mail: 1 800-282-9855 Toll Free USA/Canada Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support:

Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative